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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

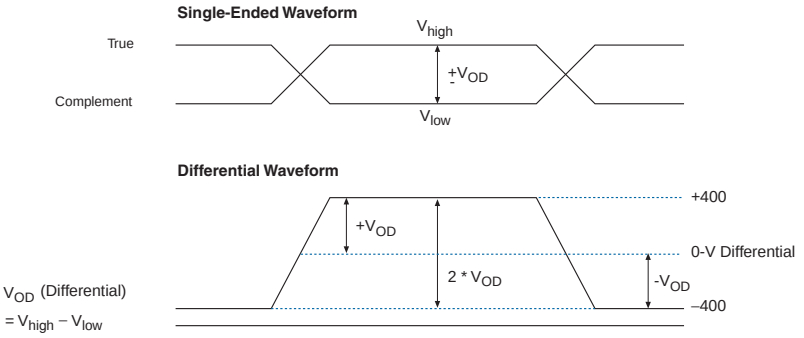
Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	4548
Number of Logic Elements/Cells	90960
Total RAM Bits	4520448
Number of I/O	558
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1152-BBGA
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2sgx90ef1152i4n

Differential signaling conventions are shown in Figure 2–9. The differential amplitude represents the value of the voltage between the true and complement signals. Peak-to-peak differential voltage is defined as $2 \times (V_{HIGH} - V_{LOW}) = 2 \times$ single-ended voltage swing. The common mode voltage is the average of V_{high} and V_{low}.

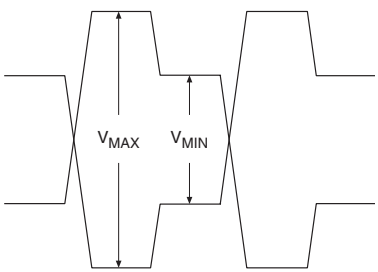
Figure 2–9. Differential Signaling



Programmable Pre-Emphasis

The programmable pre-emphasis module controls the output driver to boost the high frequency components, and compensate for losses in the transmission medium, as shown in Figure 2–10. The pre-emphasis is set statically using the ALT2GXB megafunction or dynamically through the dynamic reconfiguration controller.

Figure 2–10. Pre-Emphasis Signaling

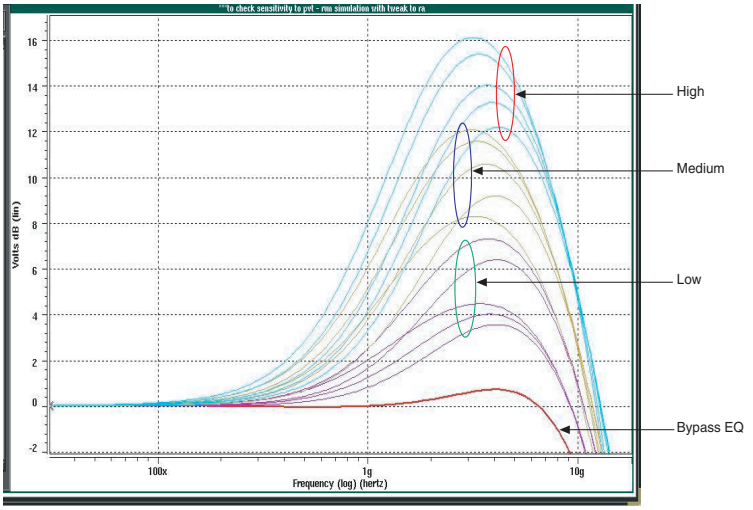


$$\text{Pre-Emphasis \%} = \left(\frac{V_{MAX}}{V_{MIN}} - 1 \right) \times 100$$

The Stratix II GX receivers also have adaptive equalization capability that adjusts the equalization levels to compensate for changing link characteristics. The adaptive equalization can be powered down dynamically after it selects the appropriate equalization levels.

The receiver equalization circuit is comprised of a programmable amplifier. Each stage is a peaking equalizer with a different center frequency and programmable gain. This allows varying amounts of gain to be applied, depending on the overall frequency response of the channel loss. Channel loss is defined as the summation of all losses through the PCB traces, vias, connectors, and cables present in the physical link. Figure 2–15 shows the frequency response for the 16 programmable settings allowed by the Quartus II software for Stratix II GX devices.

Figure 2–15. Frequency Response



Receiver PLL and CRU

Each transceiver block has four receiver PLLs, lock detectors, signal detectors, run length checkers, and CRU units, each of which is dedicated to a receive channel. If the receive channel associated with a particular receiver PLL or CRU is not used, the receiver PLL and CRU are powered down for the channel. Figure 2–16 shows the receiver PLL and CRU circuits.

This module detects word boundaries for the 8B/10B-based protocols, SONET, 16-bit, and 20-bit proprietary protocols. This module is also used to align to specific programmable patterns in PRBS7/23 test mode.

Pattern Detection

The programmable pattern detection logic can be programmed to align word boundaries using a single 7-, 8-, 10-, 16-, 20, or 32-bit pattern. The pattern detector can either do an exact match, or match the exact pattern and the complement of a given pattern. Once the programmed pattern is found, the data stream is aligned to have the pattern on the LSB portion of the data output bus.

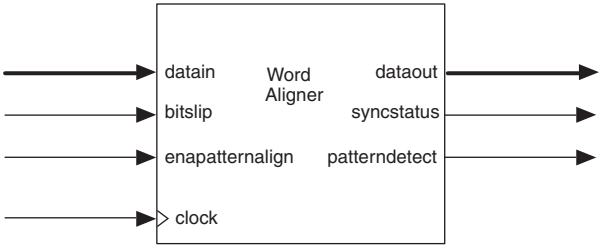
XAUI, GIGE, PCI Express, and Serial RapidIO standards have embedded state machines for symbol boundary synchronization. These standards use K28.5 as their 10-bit programmed comma pattern. Each of these standards uses different algorithms before signaling symbol boundary acquisition to the FPGA.

The pattern detection logic searches from the LSB to the most significant bit (MSB). If multiple patterns are found within the search window, the pattern in the lower portion of the data stream (corresponding to the pattern received earlier) is aligned and the rest of the matching patterns are ignored.

Once a pattern is detected and the data bus is aligned, the word boundary is locked. The two detection status signals (`rx_syncstatus` and `rx_patterndetect`) indicate that an alignment is complete.

Figure 2–18 is a block diagram of the word aligner.

Figure 2–18. Word Aligner



asynchronous clear, asynchronous preset/load, synchronous clear, synchronous load, and clock enable control for the register. These LAB wide signals are available in all ALM modes. Refer to "LAB Control Signals" on page 2–46 for more information on the LAB-wide control signals.

The Quartus II software and supported third-party synthesis tools, in conjunction with parameterized functions such as library of parameterized modules (LPM) functions, automatically choose the appropriate mode for common functions such as counters, adders, subtractors, and arithmetic functions. If required, you can also create special-purpose functions that specify which ALM operating mode to use for optimal performance.

Normal Mode

The normal mode is suitable for general logic applications and combinational functions. In this mode, up to eight data inputs from the LAB local interconnect are inputs to the combinational logic. The normal mode allows two functions to be implemented in one Stratix II GX ALM, or an ALM to implement a single function of up to six inputs. The ALM can support certain combinations of completely independent functions and various combinations of functions which have common inputs. Figure 2–37 shows the supported LUT combinations in normal mode.

R24 row interconnects span 24 LABs and provide the fastest resource for long row connections between LABs, TriMatrix memory, DSP blocks, and Row IOEs. The R24 row interconnects can cross M-RAM blocks. R24 row interconnects drive to other row or column interconnects at every fourth LAB and do not drive directly to LAB local interconnects. R24 row interconnects drive LAB local interconnects via R4 and C4 interconnects. R24 interconnects can drive R24, R4, C16, and C4 interconnects. The column interconnect operates similarly to the row interconnect and vertically routes signals to and from LABs, TriMatrix memory, DSP blocks, and IOEs. Each column of LABs is served by a dedicated column interconnect.

These column resources include:

- Shared arithmetic chain interconnects in a LAB
- Carry chain interconnects in a LAB and from LAB to LAB
- Register chain interconnects in a LAB
- C4 interconnects traversing a distance of four blocks in an up and down direction
- C16 column interconnects for high-speed vertical routing through the device

Stratix II GX devices include an enhanced interconnect structure in LABs for routing shared arithmetic chains and carry chains for efficient arithmetic functions. The register chain connection allows the register output of one ALM to connect directly to the register input of the next ALM in the LAB for fast shift registers. These ALM-to-ALM connections bypass the local interconnect. The Quartus II Compiler automatically takes advantage of these resources to improve utilization and performance. Figure 2–47 shows the shared arithmetic chain, carry chain, and register chain interconnects.

The DSP block is divided into four block units that interface with four LAB rows on the left and right. Each block unit can be considered one complete 18 × 18-bit multiplier with 36 inputs and 36 outputs. A local interconnect region is associated with each DSP block. Like a LAB, this interconnect region can be fed with 16 direct link interconnects from the LAB to the left or right of the DSP block in the same row. R4 and C4 routing resources can access the DSP block's local interconnect region. The outputs also work similarly to LAB outputs. Eighteen outputs from the DSP block can drive to the left LAB through direct link interconnects and 18 can drive to the right LAB through direct link interconnects. All 36 outputs can drive to R4 and C4 routing interconnects. Outputs can drive right- or left-column routing.

Figures 2–59 and 2–60 show the DSP block interfaces to LAB rows.

Figure 2–59. DSP Block Interconnect Interface

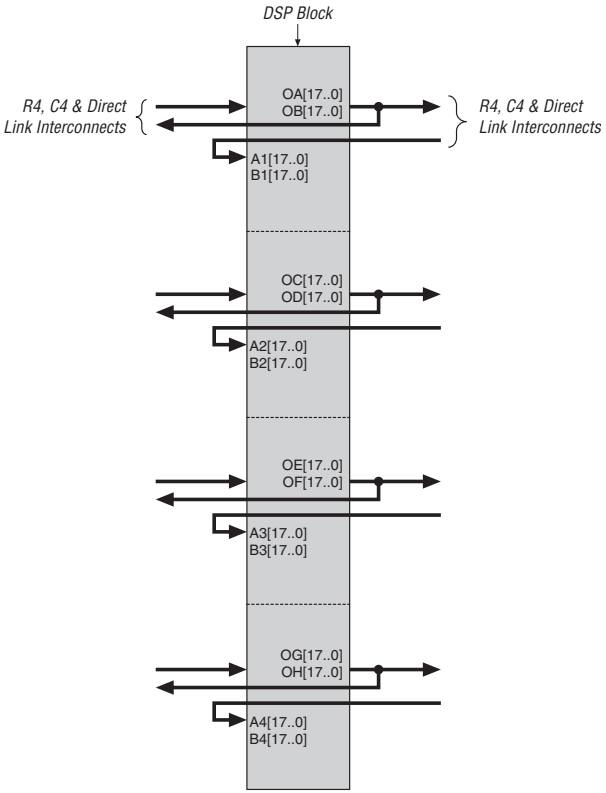
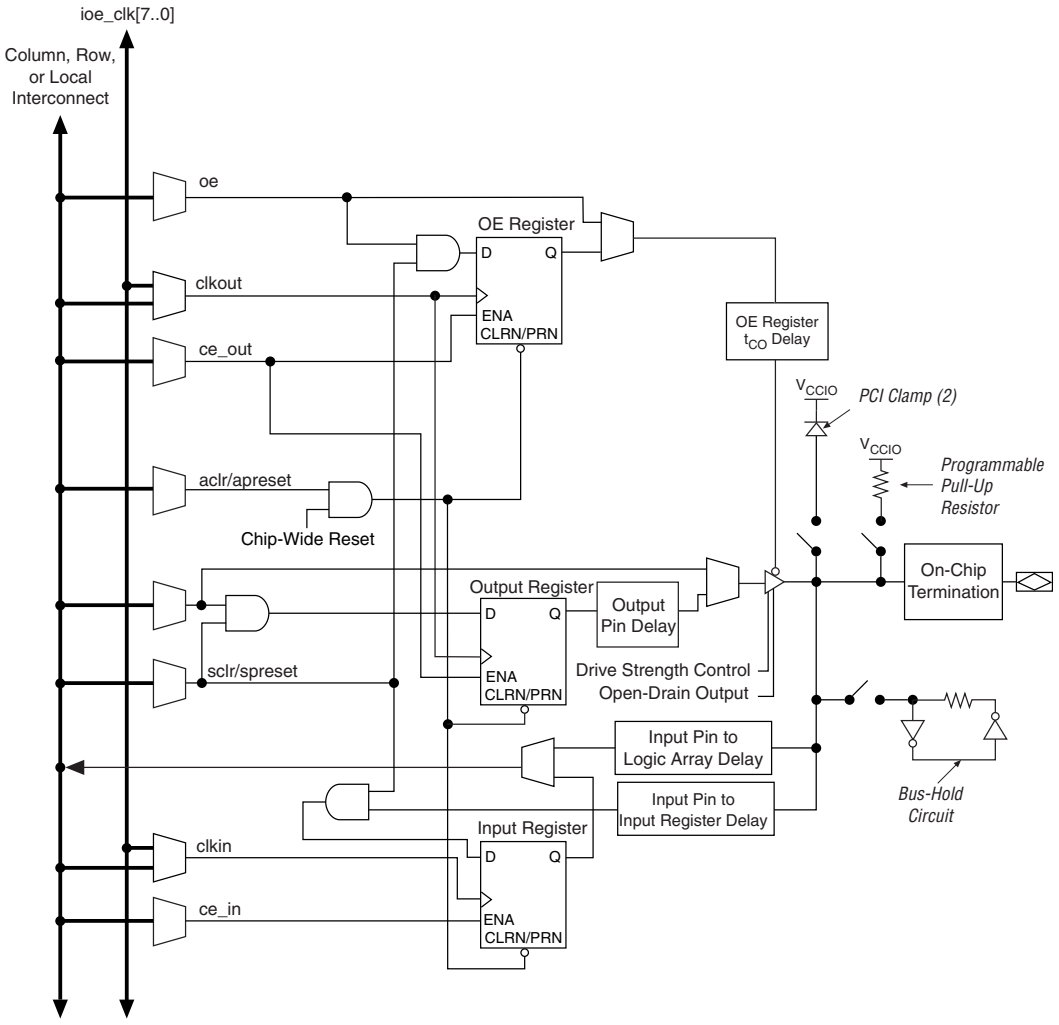


Figure 2–81. Stratix II GX IOE in Bidirectional I/O Configuration *Note (1)*



Notes to Figure 2–81:
(1) All input signals to the IOE can be inverted at the IOE.
(2) The optional PCI clamp is only available on column I/O pins.

The Stratix II GX device IOE includes programmable delays that can be activated to ensure input IOE register-to-logic array register transfers, input pin-to-logic array register transfers, or output IOE register-to-pin transfers.

A path in which a pin directly drives a register can require the delay to ensure zero hold time, whereas a path in which a pin drives a register through combinational logic may not require the delay. Programmable delays exist for decreasing input-pin-to-logic-array and IOE input register delays. The Quartus II Compiler can program these delays to automatically minimize setup time while providing a zero hold time. Programmable delays can increase the register-to-pin delays for output and/or output enable registers. Programmable delays are no longer required to ensure zero hold times for logic array register-to-IOE register transfers. The Quartus II Compiler can create the zero hold time for these transfers. Table 2–30 shows the programmable delays for Stratix II GX devices.

Table 2–30. Stratix II GX Programmable Delay Chain

Programmable Delays	Quartus II Logic Option
Input pin to logic array delay	Input delay from pin to internal cells
Input pin to input register delay	Input delay from pin to input register
Output pin delay	Delay from output register to output pin
Output enable register t_{CO} delay	Delay to output enable pin

The IOE registers in Stratix II GX devices share the same source for clear or preset. You can program preset or clear for each individual IOE. You can also program the registers to power up high or low after configuration is complete. If programmed to power up low, an asynchronous clear can control the registers. If programmed to power up high, an asynchronous preset can control the registers. This feature prevents the inadvertent activation of another device's active-low input upon power-up. If one register in an IOE uses a preset or clear signal, all registers in the IOE must use that same signal if they require preset or clear. Additionally, a synchronous reset signal is available for the IOE registers.

Double Data Rate I/O Pins

Stratix II GX devices have six registers in the IOE, which support DDR interfacing by clocking data on both positive and negative clock edges. The IOEs in Stratix II GX devices support DDR inputs, DDR outputs, and bidirectional DDR modes. When using the IOE for DDR inputs, the two input registers clock double rate input data on alternating edges. An input latch is also used in the IOE for DDR input acquisition. The latch holds the data that is present during the clock high times, allowing both bits of data to be synchronous with the same clock edge (either rising or falling). Figure 2–82 shows an IOE configured for DDR input. Figure 2–83 shows the DDR input timing diagram.

Table 2–33. Stratix II GX Supported I/O Standards

I/O Standard	Type	Input Reference Voltage (V_{REF}) (V)	Output Supply Voltage (V_{CCIO}) (V)	Board Termination Voltage (V_{TT}) (V)
SSTL-2 class I and II	Voltage-referenced	1.25	2.5	1.25

Notes to Table 2–33:
(1) This I/O standard is only available on input and output column clock pins.
(2) This I/O standard is only available on input clock pins and DQS pins in I/O banks 3, 4, 7, and 8, and output clock pins in I/O banks 9,10, 11, and 12.
(3) V_{CCIO} is 3.3 V when using this I/O standard in input and output column clock pins (in I/O banks 3, 4, 7, 8, 9, 10, 11, and 12).
(4) 1.2-V HSTL is only supported in I/O banks 4, 7, and 8.

For more information on I/O standards supported by Stratix II GX I/O banks, refer to the *Selectable I/O Standards in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II GX Device Handbook*.

Stratix II GX devices contain six I/O banks and four enhanced PLL external clock output banks, as shown in Figure 2–87. The two I/O banks on the left of the device contain circuitry to support source-synchronous, high-speed differential I/O for LVDS inputs and outputs. These banks support all Stratix II GX I/O standards except PCI or PCI-X I/O pins, and SSTL-18 class II and HSTL outputs. The top and bottom I/O banks support all single-ended I/O standards. Additionally, enhanced PLL external clock output banks allow clock output capabilities such as differential support for SSTL and HSTL.

For more information on tolerance specifications for differential on-chip termination, refer to the *DC & Switching Characteristics* chapter in volume 1 of the *Stratix II GX Device Handbook*.

On-Chip Series Termination without Calibration

Stratix II GX devices support driver impedance matching to provide the I/O driver with controlled output impedance that closely matches the impedance of the transmission line. As a result, reflections can be significantly reduced. Stratix II GX devices support on-chip series termination for single-ended I/O standards with typical R_S values of 25 and 50 Ω. Once matching impedance is selected, current drive strength is no longer selectable. Table 2–34 shows the list of output standards that support on-chip series termination without calibration.

For more information about series on-chip termination supported by Stratix II GX devices, refer to the *Selectable I/O Standards in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II GX Device Handbook*.

For more information about tolerance specifications for on-chip termination without calibration, refer to the *DC & Switching Characteristics* chapter in volume 1 of the *Stratix II GX Device Handbook*.

On-Chip Series Termination with Calibration

Stratix II GX devices support on-chip series termination with calibration in column I/O pins in top and bottom banks. There is one calibration circuit for the top I/O banks and one circuit for the bottom I/O banks. Each on-chip series termination calibration circuit compares the total impedance of each I/O buffer to the external 25-Ω or 50-Ω resistors connected to the `RUP` and `RDN` pins, and dynamically enables or disables the transistors until they match. Calibration occurs at the end of device configuration. Once the calibration circuit finds the correct impedance, it powers down and stops changing the characteristics of the drivers.

For more information about series on-chip termination supported by Stratix II GX devices, refer to the *Selectable I/O Standards in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II GX Device Handbook*.

For more information about tolerance specifications for on-chip termination with calibration, refer to the *DC & Switching Characteristics* chapter in volume 1 of the *Stratix II GX Device Handbook*.

- *Stratix II Performance and Logic Efficiency Analysis White Paper*
- *TriMatrix Embedded Memory Blocks in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II GX Device Handbook*

Document Revision History

Table 2–42 shows the revision history for this chapter.

Table 2–42. Document Revision History (Part 1 of 6)

Date and Document Version	Changes Made	Summary of Changes
October 2007, v2.2	Updated: • "Programmable Pull-Up Resistor" • "Reverse Serial Pre-CDR Loopback" • "Receiver Input Buffer" • "Pattern Detection" • "Control and Status Signals" • "Individual Power Down and Reset for the Transmitter and Receiver"	
	Updated: • Figure 2–14 • Figure 2–26 • Figure 2–27 • Figure 2–86 (notes only) • Figure 2–87	
	Updated: • Table 2–4 • Table 2–7	
	Removed note from Table 2–31.	
	Removed Tables 2-2, 2-7, and 2-8.	
	Minor text edits.	
August 2007, v2.1	Added "Reverse Serial Pre-CDR Loopback" section.	
	Updated Table 2–2.	
	Added "Referenced Documents" section.	

Table 2–42. Document Revision History (Part 5 of 6)

Date and Document Version	Changes Made	Summary of Changes
Previous Chapter 02 changes: June 2006, v1.2	• Updated notes 1 and 2 in Figure 2–1. • Updated "Byte Serializer" section. • Updated Tables 2–4, 2–7, and 2–16. • Updated "Programmable Output Driver" section. • Updated Figure 2–12. • Updated "Programmable Pre-Emphasis" section. • Added Table 2–11. • Added "Dynamic Reconfiguration" section. • Added "Calibration Block" section. • Updated "Programmable Equalizer" section, including addition of Figure 2–18.	Updated input frequency range in Table 2–4.
Previous Chapter 02 changes: April 2006, v1.1	• Updated Figure 2–3. • Updated Figure 2–7. • Updated Table 2–4. • Updated "Transmit Buffer" section.	Updated input frequency range in Table 2–4.
Previous Chapter 02 changes: October 2005 v1.0	Added chapter to the *Stratix II GX Device Handbook*.	
Previous Chapter 03 changes: August 2006, v1.4	• Updated Table 3–18 with note.	
Previous Chapter 03 changes: June 2006, v1.3	• Updated note 2 in Figure 3–41. • Updated column title in Table 3–21.	
Previous Chapter 03 changes: April 2006, v1.2	• Updated note 1 in Table 3–9. • Updated note 1 in Figure 3–40. • Updated note 2 in Figure 3–41. • Updated Table 3–16. • Updated Figure 3–56. • Updated Tables 3–19 through 3–22. • Updated Tables 3–25 and 3–26. • Updated "Fast PLL & Channel Layout" section.	Added 1,152-pin FineLine BGA package information for EP2SGX60 device in Table 3–16.

Table 4–8. Typical V_{OD} Setting, TX Term = 120 Ω Note (1)					
V_{CCH} TX = 1.5 V	**V_{OD} Setting (mV)**				
	240	**480**	**720**	**960**	**1200**
V_{OD} Typical (mV)	260	510	750	975	1200

Note to Table 4–8:
(1) Applicable to data rates from 600 Mbps to 6.375 Gbps. Specification is for measurement at the package ball.

Table 4–9. Typical V_{OD} Setting, TX Term = 150 Ω Note (1)				
V_{CCH} TX = 1.5 V	**V_{OD} Setting (mV)**			
	300	**600**	**900**	**1200**
V_{OD} Typical (mV)	325	625	920	1200

Note to Table 4–9:
(1) Applicable to data rates from 600 Mbps to 6.375 Gbps. Specification is for measurement at the package ball.

Table 4–10. Typical V_{OD} Setting, TX Term = 100 Ω Note (1)					
V_{CCH} TX = 1.2 V	**V_{OD} Setting (mV)**				
	320	**480**	**640**	**800**	**960**
V_{OD} Typical (mV)	344	500	664	816	960

Note to Table 4–10:
(1) Applicable to data rates from 600 Mbps to 3.125 Gbps. Specification is for measurement at the package ball.

Table 4–15. Typical Pre-Emphasis (First Post-Tap), Note (1) (Part 2 of 2)

V_{CCH} TX = 1.5 V	First Post Tap Pre-Emphasis Level											
V_{OD} Setting (mV)	1	2	3	4	5	6	7	8	9	10	11	12
600		33%	53%	80%	115%	157%	195%	294%	386%			
900		19%	28%	38%	56%	70%	86%	113%	133%	168%	196%	242%
1200			17%	22%	31%	40%	52%	62%	75%	86%	96%	112%

Note to Table 4–15:
(1) Applicable to data rates from 600 Mbps to 6.375 Gbps. Specification is for measurement at the package ball.

Table 4–16. Typical Pre-Emphasis (First Post-Tap), Note (1)

V_{CCH} TX = 1.2 V	First Post Tap Pre-Emphasis Level											
V_{OD} Setting (mV)	1	2	3	4	5	6	7	8	9	10	11	12
	TX Term = 100 Ω											
320	24%	61%	114%									
480		31%	55%	86%	121%	170%	232%	333%				
640		20%	35%	54%	72%	95%	124%	157%	195%	233%	307%	373%
800			23%	36%	49%	64%	81%	97%	117%	140%	161%	195%
960			18%	25%	35%	44%	57%	69%	82%	94%	108%	127%

Note to Table 4–16:
(1) Applicable to data rates from 600 Mbps to 3.125 Gbps. Specification is for measurement at the package ball.

Table 4–37. SSTL-18 Class I and II Differential Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.71	1.8	1.89	V
V_{SWING} (DC)	DC differential input voltage		0.25			V
V_X (AC)	AC differential input cross point voltage		(V_{CCIO}/2) – 0.175		(V_{CCIO}/2) + 0.175	V
V_{SWING} (AC)	AC differential input voltage		0.5			V
V_{ISO}	Input clock signal offset voltage			0.5 V_{CCIO}		V
ΔV_{ISO}	Input clock signal offset voltage variation			200		mV
V_{OX} (AC)	AC differential cross point voltage		(V_{CCIO}/2) – 0.125		(V_{CCIO}/2) + 0.125	V

Table 4–38. SSTL-2 Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		2.375	2.5	2.625	V
V_{TT}	Termination voltage		V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04	V
V_{REF}	Reference voltage		1.188	1.25	1.313	V
V_{IH} (DC)	High-level DC input voltage		V_{REF} + 0.18		3.0	V
V_{IL} (DC)	Low-level DC input voltage		–0.3		V_{REF} – 0.18	V
V_{IH} (AC)	High-level AC input voltage		V_{REF} + 0.35			V
V_{IL} (AC)	Low-level AC input voltage				V_{REF} – 0.35	V
V_{OH}	High-level output voltage	I_{OH} = –8.1 mA *(1)*	V_{TT} + 0.57			V
V_{OL}	Low-level output voltage	I_{OL} = 8.1 mA *(1)*			V_{TT} – 0.57	V

Note to Table 4–38:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II GX Architecture* chapter in volume 1 of the *Stratix II GX Device Handbook*.

Table 4–39. SSTL-2 Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		2.375	2.5	2.625	V
V_{TT}	Termination voltage		V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04	V
V_{REF}	Reference voltage		1.188	1.25	1.313	V

Table 4–59. M512 Block Internal Timing Microparameters (Part 1 of 2)

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{M512RC}	Synchronous read cycle time	2089	2318	2089	2433	2089	2587	2089	3104	ps
$t_{M512WERESU}$	Write or read enable setup time before clock	22		23		24		29		ps
$t_{M512WEREH}$	Write or read enable hold time after clock	203		213		226		272		ps
$t_{M512DATASU}$	Data setup time before clock	22		23		24		29		ps
$t_{M512DATAH}$	Data hold time after clock	203		213		226		272		ps
$t_{M512WADDRSU}$	Write address setup time before clock	22		23		24		29		ps
$t_{M512WADDRH}$	Write address hold time after clock	203		213		226		272		ps
$t_{M512RADDRSU}$	Read address setup time before clock	22		23		24		29		ps
$t_{M512RADDRH}$	Read address hold time after clock	203		213		226		272		ps
$t_{M512DATACO1}$	Clock-to-output delay when using output registers	298	478	298	501	298	533	298	640	ps
$t_{M512DATACO2}$	Clock-to-output delay without output registers	2102	2345	2102	2461	2102	2616	2102	3141	ps
$t_{M512CLKL}$	Minimum clock low time	1315		1380		1468		1762		ps
$t_{M512CLKH}$	Minimum clock high time	1315		1380		1468		1762		ps

Stratix II GX Clock Timing Parameters

See Tables 4–62 through 4–78 for Stratix II GX clock timing parameters.

Table 4–62. Stratix II GX Clock Timing Parameters

Symbol	Parameter
t_{CIN}	Delay from clock pad to I/O input register
t_{COUT}	Delay from clock pad to I/O output register
t_{PLLCIN}	Delay from PLL `inclk` pad to I/O input register
$t_{PLLCOUT}$	Delay from PLL `inclk` pad to I/O output register

EP2SGX30 Clock Timing Parameters

Tables 4–63 through 4–66 show the maximum clock timing parameters for EP2SGX30 devices.

Table 4–63. EP2SGX30 Column Pins Global Clock Timing Parameters

Parameter	Fast Corner		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Units
	Industrial	Commercial				
t_{CIN}	1.615	1.633	2.669	2.968	3.552	ns
t_{COUT}	1.450	1.468	2.427	2.698	3.228	ns
t_{PLLCIN}	0.11	0.129	0.428	0.466	0.547	ns
$t_{PLLCOUT}$	-0.055	-0.036	0.186	0.196	0.223	ns

Table 4–64. EP2SGX30 Row Pins Global Clock Timing Parameters

Parameter	Fast Corner		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Units
	Industrial	Commercial				
t_{CIN}	1.365	1.382	2.280	2.535	3.033	ns
t_{COUT}	1.370	1.387	2.276	2.531	3.028	ns
t_{PLLCIN}	-0.151	-0.136	0.043	0.037	0.032	ns
$t_{PLLCOUT}$	-0.146	-0.131	0.039	0.033	0.027	ns

Table 4–65. EP2SGX30 Column Pins Regional Clock Timing Parameters

Parameter	Fast Corner		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Units
	Industrial	Commercial				
t_{CIN}	1.493	1.507	2.522	2.806	3.364	ns
t_{COUT}	1.353	1.372	2.525	2.809	3.364	ns
t_{PLLCIN}	0.087	0.104	0.237	0.253	0.292	ns
$t_{PLLCOUT}$	-0.078	-0.061	0.237	0.253	0.29	ns

Table 4–66. EP2SGX30 Row Pins Regional Clock Timing Parameters

Parameter	Fast Corner		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Units
	Industrial	Commercial				
t_{CIN}	1.246	1.262	2.437	2.712	3.246	ns
t_{COUT}	1.251	1.267	2.437	2.712	3.246	ns
t_{PLLCIN}	-0.18	-0.167	0.215	0.229	0.263	ns
$t_{PLLCOUT}$	-0.175	-0.162	0.215	0.229	0.263	ns

EP2SGX60 Clock Timing Parameters

Tables 4–67 through 4–70 show the maximum clock timing parameters for EP2SGX60 devices.

Table 4–67. EP2SGX60 Column Pins Global Clock Timing Parameters

Parameter	Fast Corner		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Units
	Industrial	Commercial				
t_{CIN}	1.722	1.736	2.940	3.275	3.919	ns
t_{COUT}	1.557	1.571	2.698	3.005	3.595	ns
t_{PLLCIN}	0.037	0.051	0.474	0.521	0.613	ns
$t_{PLLCOUT}$	-0.128	-0.114	0.232	0.251	0.289	ns

Table 4–91. Stratix II GX Maximum Output Clock Rate for Column Pins (Part 2 of 3)					
I/O Standard	**Drive Strength**	**-3 Speed Grade**	**-4 Speed Grade**	**-5 Speed Grade**	**Unit**
SSTL-18 Class I	4 mA	200	150	150	MHz
	6 mA	350	250	200	MHz
	8 mA	450	300	300	MHz
	10 mA	500	400	400	MHz
	12 mA *(1)*	700	550	400	MHz
SSTL-18 Class II	8 mA	200	200	150	MHz
	16 mA	400	350	350	MHz
	18 mA	450	400	400	MHz
	20 mA *(1)*	550	500	450	MHz
1.8-V HSTL Class I	4 mA	300	300	300	MHz
	6 mA	500	450	450	MHz
	8 mA	650	600	600	MHz
	10 mA	700	650	600	MHz
	12 mA *(1)*	700	700	650	MHz
1.8-V HSTL Class II	16 mA	500	500	450	MHz
	18 mA	550	500	500	MHz
	20 mA *(1)*	650	550	550	MHz
1.5-V HSTL Class I	4 mA	350	300	300	MHz
	6 mA	500	500	450	MHz
	8 mA	700	650	600	MHz
	10 mA	700	700	650	MHz
	12 mA *(1)*	700	700	700	MHz
1.5-V HSTL Class II	16 mA	600	600	550	MHz
	18 mA	650	600	600	MHz
	20 mA *(1)*	700	650	600	MHz
PCI	-	1000	790	670	MHz
PCI-X	-	1000	790	670	MHz
Differential SSTL-2 Class I	8 mA	400	300	300	MHz
	12 mA	400	400	350	MHz
Differential SSTL-2 Class II	16 mA	350	350	300	MHz
	20 mA	400	350	350	MHz
	24 mA	400	400	350	MHz

Table 4–105. Maximum DCD for DDIO Output on Column I/O Pins With PLL in the Clock Path (Part 2 of 2)			
Maximum DCD (ps) for Column DDIO Output I/O Standard	Stratix II GX Devices (PLL Output Feeding DDIO)		Unit
	-3 Device	-4 and -5 Device	
1.2-V HSTL	155	155	ps
LVPECL	180	180	ps

High-Speed I/O Specifications

Table 4–106 provides high-speed timing specifications definitions.

Table 4–106. High-Speed Timing Specifications and Definitions	
High-Speed Timing Specifications	Definitions
t_C	High-speed receiver/transmitter input and output clock period.
f_{HSCLK}	High-speed receiver/transmitter input and output clock frequency.
J	Deserialization factor (width of parallel data bus).
W	PLL multiplication factor.
t_{RISE}	Low-to-high transmission time.
t_{FALL}	High-to-low transmission time.
Timing unit interval (TUI)	The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = 1/(Receiver Input Clock Frequency × Multiplication Factor) = t_C/w).
f_{IN}	Fast PLL input clock frequency
f_{HSDR}	Maximum/minimum LVDS data transfer rate (f_{HSDR} = 1/TUI), non-DPA.
$f_{HSDRDPA}$	Maximum/minimum LVDS data transfer rate ($f_{HSDRDPA}$ = 1/TUI), DPA.
Channel-to-channel skew (TCCS)	The timing difference between the fastest and the slowest output edges including t_{CO} variation and clock skew across channels driven by the same fast PLL. The clock is included in the TCCS measurement.
Sampling window (SW)	The period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window.
Input jitter	Peak-to-peak input jitter on high-speed PLLs.
Output jitter	Peak-to-peak output jitter on high-speed PLLs.
t_{DUTY}	Duty cycle on high-speed transmitter output clock.
t_{LOCK}	Lock time for high-speed transmitter and receiver PLLs.